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First edition
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Calibration of optical spectrum analyzers

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CONTENTS

FOREWORD.....	5
1 Scope.....	5
2 Normative references.....	5
3 Definitions.....	6
4 Calibration test requirements.....	9
4.1 Preparation.....	9
4.2 Reference test conditions.....	10
4.3 Traceability.....	10
5 Resolution bandwidth (spectral resolution) test.....	10
5.1 Overview.....	10
5.2 Resolution bandwidth (spectral resolution) test.....	10
5.2.1 Equipment for resolution bandwidth (spectral resolution) test.....	11
5.2.2 Test procedure for resolution bandwidth (spectral resolution).....	12
6 Displayed power level calibration.....	13
6.1 Overview.....	13
6.2 Displayed power level (DPL) calibration under reference conditions.....	13
6.2.1 Equipment for DPL calibration under reference conditions.....	13
6.2.2 Test procedure for DPL calibration under reference conditions.....	14
6.2.3 Calculation of DPL uncertainty under reference conditions.....	14
6.3 Displayed power level (DPL) calibration for operating conditions.....	15
6.3.1 Wavelength dependence.....	15
6.3.2 Polarization dependence.....	16
6.3.3 Linearity.....	18
6.3.4 Temperature dependence.....	19
6.4 Calculation of expanded uncertainty in displayed power level.....	20
7 Wavelength calibration.....	21
7.1 Overview.....	21
7.2 Wavelength calibration under reference conditions.....	21
7.2.1 Equipment for wavelength calibration under reference conditions.....	21
7.2.2 Test procedure for wavelength calibration under reference conditions.....	22
7.2.3 Calculations of wavelength uncertainty under reference conditions.....	22
7.3 Wavelength calibration for operating conditions.....	23
7.3.1 Wavelength dependence.....	23
7.3.2 Temperature dependence.....	24
7.4 Calculation of expanded uncertainty in wavelength.....	25
8 Documentation.....	25
8.1 Measurement data and uncertainty.....	25
8.2 Measurement conditions.....	26
Annex A (normative) Mathematical basis for calculation of calibration uncertainty.....	27
A.1 Deviations.....	27
A.2 Uncertainty type A.....	27
A.3 Uncertainty type B.....	28
A.4 Accumulation of uncertainties.....	29
A.5 Reporting.....	30

Annex B (informative) Examples of calculation of calibration uncertainty	31
B.1 Displayed power level calibration	31
B.1.1 Uncertainty under reference conditions: $\sigma_{\Delta P_{ref}}$	31
B.1.2 Uncertainty under operating conditions	32
B.1.3 Expanded uncertainty calculation	35
B.2 Wavelength calibration	35
B.2.1 Uncertainty under reference conditions: $\sigma_{\Delta \lambda_{ref}}$	35
B.2.2 Uncertainty under operating conditions	36
B.2.3 Expanded uncertainty calculation	37
Annex C (informative) Using the calibration results	39
C.1 General	39
C.1.1 Scope 39	
C.1.2 Parameters	39
C.1.3 Restrictions	39
C.2 Additive corrections	39
C.2.1 Parameters	39
C.2.2 Measurements close to a calibration reference wavelength	40
C.2.3 Measurements at other wavelengths	40
C.3 Multiplicative corrections	41
C.3.1 Parameters	41
C.3.2 Measurements close to a calibration reference wavelength	41
C.3.3 Measurements at other wavelengths	41
C.4 OSA calibration results (additive correction)	42
Annex D (informative) Wavelength references	44
D.1 Gas laser lines	44
D.2 Noble gas reference lines	44
D.3 Molecular absorption lines	45
D.4 Reference documents	48
Annex E (informative) Further reading and references for calibration of wavelength scale	49

INTERNATIONAL ELECTROTECHNICAL COMMISSION

CALIBRATION OF OPTICAL SPECTRUM ANALYZERS

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The text of this PAS is based on the following document:

This PAS was approved for publication by the P-members of the committee concerned as indicated in the following document

Draft PAS	Report on voting
86/202/NP	86/214/RVN

Following publication of this PAS, which is a pre-standard publication, the technical committee or subcommittee concerned will transform it into an International Standard.

CALIBRATION OF OPTICAL SPECTRUM ANALYZERS

1 Scope

This document provides procedures for calibrating an optical spectrum analyzer designed to measure the power distribution of an optical spectrum; this analyzer is equipped with an input port for use with a fibre-optic connector.

An optical spectrum analyzer is equipped with the following minimum features:

- a) the ability to present a display of an optical spectrum with respect to absolute wavelength;
- b) a marker/cursor that displays the optical power and wavelength at a point on the spectrum display.

NOTE This specification applies to optical spectrum analyzers developed for use in fibre-optic communications and is limited to equipment that can directly measure the optical spectrum output from an optical fibre, where the optical fibre is connected to an input port installed in the optical spectrum analyzer through a fibre-optic connector.

In addition, an optical spectrum analyzer can measure the spectral power distribution with respect to the absolute wavelength of the tested light and display the results of such measurements; it will not include an optical wavelength meter that measures only centre wavelengths, a Fabry-Perot interferometer or a monochromator that has no display unit.

The procedures outlined in this document are considered to be mainly performed by users of optical spectrum analyzers. The document, therefore, does not include correction using the calibration results in the main body. The correction procedures are described in Annex C. Of course, this document will be useful in calibration laboratories and for manufacturers of optical spectrum analyzers.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-731:1991, *International Electrotechnical Vocabulary (IEV) – Chapter 731: Optical fibre communication*

IEC 60359:2001, *Electrical and electronic measurement equipment – Expression of performance*

IEC 60793-1(all parts), *Optical fibres – Part 1: Measurement methods and test procedures*

IEC 60825-1:1993, *Safety of laser products – Part 1: Equipment classification, requirements and user's guide*

IEC 60825-2:2000, *Safety of laser products – Part 2: Safety of optical fibre communication systems*

IEC 61290-3-1:2003, *Optical amplifiers – Test methods – Part 3-1: Noise figure parameters – Optical spectrum analyzer method*

ISO 9000: *Quality management systems – Fundamentals and vocabulary*

ISO:1995, *Guide to the expression of uncertainty in measurement*

ISO:1993, *International vocabulary of basic and general terms in metrology*

3 Definitions

For the purposes of this document, the definitions contained in IEC 60050-731 and the following definitions apply.

3.1 calibration

set of operations which establishes, under specified conditions, the relationship between the values indicated by the measuring instrument and the corresponding known values of that quantity (see also ISO International vocabulary of basic and general terms in metrology, definition 6.11)

3.2 calibration under reference conditions

calibration which includes the evaluation of the test analyzer uncertainty under **reference conditions** (3.17)

3.3 calibration for operating conditions

calibration for operating conditions of an **optical spectrum analyzer** (3.16) including the evaluation of the test analyzer operational uncertainty

3.4 centre wavelength

λ_{centre}
power-weighted mean wavelength of a light source in a vacuum, in nanometers (nm)

For a continuous spectrum, the centre wavelength is defined as

$$\lambda_{\text{centre}} = (1 / P_{\text{total}}) \int \rho(\lambda) \lambda \, d\lambda \quad (1)$$

For a spectrum consisting of discrete lines, the centre wavelength is defined as

$$\lambda_{\text{centre}} = \sum_i P_i \lambda_i / \sum_i P_i \quad (2)$$

where

$\rho(\lambda)$ is the power spectral density of the source, for example in W/nm;

λ_j is the j^{th} discrete wavelength;

P_j is the power at λ_j , for example, in watts;

P_{total} is $\sum P_j$ = total power, for example, in watts.

NOTE The above integrals and summations theoretically extend over the entire spectrum of the light source.

3.5 confidence level

estimation of the probability that the true value of a measured parameter lies in the given range (see **expanded uncertainty** (3.11))

3.6 coverage factor

k
coverage factor, k , is used to calculate the **expanded uncertainty** (3.11) U from the **standard uncertainty** (3.21), σ (see 3.11)

3.7 displayed power level DPL

power level indicated by an **optical spectrum analyzer** (3.16) undergoing **calibration** (3.1) at a specified wavelength resolution setting

NOTE With an **optical spectrum analyzer**, the power level for a set resolution is measured and displayed.

3.8 displayed power level deviation ΔP

difference between the displayed power level measured by the test analyzer, P_{OSA} , and the corresponding reference power, P_{ref} , divided by the reference power

$$\Delta P = (P_{OSA} - P_{ref}) / P_{ref} = P_{OSA} / P_{ref} - 1 \quad (3)$$

3.9 displayed power level uncertainty, symbol $\sigma_{\Delta P}$ standard uncertainty (3.21) of the displayed power level deviation

$$\sigma_{\Delta P} = \sigma(P_{OSA} / P_{ref} - 1) \quad (4)$$

NOTE In the above formula, σ is to be understood as the **standard uncertainty** (3.21).

3.10 displayed wavelength range

complete wavelength range shown in an **optical spectrum analyzer** (3.16) display for a particular **instrument state** (3.12)

3.11 expanded uncertainty U

expanded uncertainty, U (also called the confidence interval) is the range of values within which the measurement parameter, at the stated **confidence level** (3.5), can be expected to lie. It is equal to the **coverage factor** (3.6), k , times the combined **standard uncertainty** (3.21) σ :

$$U = k \sigma \quad (5)$$

NOTE When the distribution of uncertainties is assumed to be normal and a large number of measurements are made, then **confidence levels** (3.5) of 68,3 %, 95,5 % and 99,7 % correspond to k values of 1, 2 and 3 respectively.

The measurement uncertainty of an **optical spectrum analyzer** (3.16) should be specified in the form of expanded uncertainty, U .

3.12 instrument state

complete description of the measurement conditions and state of an **optical spectrum analyzer** (3.16) during the calibration process

NOTE Typical parameters of the instrument state are the **displayed wavelength range** (3.10) in use, the **resolution bandwidth (spectral resolution)** (3.18), the display mode (watt or dBm), warm-up time and other instrument settings.

3.13 measurement result

displayed or electrical output of any **optical spectrum analyzer** (3.16) in wavelength, in units of nm or μm , and in power level, in units of mW or dBm, after completing all operations suggested by the operating instructions, for example warm-up

3.14

measurement wavelength range

wavelength range of injected light over which an **optical spectrum analyzer** (3.16) performance is specified

3.15

operating conditions

all conditions of the measured and influential qualities, and other important requirements which the **expanded uncertainty** (3.11) of an **optical spectrum analyzer** (3.16) is intended to be met (modified from ISO International vocabulary of basic and general terms in metrology, definition 5.5)

3.16

optical spectrum analyzer

OSA

optical instrument for measuring the power distribution of a spectrum with respect to wavelength (frequency)

NOTE An OSA is equipped with an input port for use with a fibre-optic connector, and the spectrum is obtained from light injected into the input port; the instrument also includes a screen-display function.

3.17

reference conditions

appropriate set of influencing parameters, their nominal values and their tolerance bands, with respect to which the uncertainty at reference conditions is specified (modified from IEC 60359, 3.3.10)

NOTE Each tolerance band includes both the possible uncertainty of the condition and the uncertainty in measuring the condition.

The reference conditions normally include the following parameters and, if necessary, their tolerance bands: reference date, reference temperature, reference humidity, reference atmospheric pressure, reference light source, reference **displayed power level** (3.7), reference fibre, reference connector-adaptor combination, reference wavelength, reference (spectral) bandwidth and **resolution bandwidth (spectral resolution)** (3.18) set.

3.18

resolution bandwidth (spectral resolution)

R

full width at half maximum (FWHM) of the displayed spectrum obtained by the test analyzer when using a source whose **spectral bandwidth** (3.20) is sufficiently narrow, that is, very much less than the resolution bandwidth being measured

3.19

side-mode suppression ratio

SMSR

peak power ratio between the main mode spectrum and the largest side mode spectrum in a single-mode laser diode such as a DFB-LD

NOTE The side-mode suppression ratio is usually described in dB.

3.20

spectral bandwidth

B

for the purpose of this document, the FWHM of the spectral width of the source.

If the source exhibits a continuous spectrum, then the spectral bandwidth, *B*, is the FWHM of the spectrum.

If the source is a laser diode with a multiple-longitudinal mode spectrum, then the FWHM spectral bandwidth *B* is the RMS spectral bandwidth, multiplied by 2,35 (assuming the source has a Gaussian envelope):

$$B = 2,35 \left[\left(\frac{1}{P_{\text{total}}} \right) \times \left[\sum_i P_i \lambda_i^2 \right] \right] - \lambda_{\text{centre}}^2 \right]^{1/2} \quad (6)$$

where

λ_{centre} is the **centre wavelength** (3.4) of laser diode, in nm;

P_{total} is $\sum P_j$ = total power, in watts;

P_j is the power of i^{th} longitudinal mode, in watts;

λ_j is the wavelength of i^{th} longitudinal mode, in nm.

3.21

standard uncertainty

σ

uncertainty of a measurement result expressed as a standard deviation

NOTE For further information, see Annex A and the ISO Guide to the expression of uncertainty in measurement.

3.22

uncertainty type A

type of uncertainty obtained by a statistical analysis of a series of observations, such as when evaluating certain random effects of measurement (see ISO Guide to the expression of uncertainty in measurement)

3.23

uncertainty type B

type of uncertainty obtained by means other than a statistical analysis of observations, for example an estimation of probable sources of uncertainty, such as when evaluating systematic effects of measurement (see ISO Guide to the expression of uncertainty in measurement)

NOTE Other means may include previous measurement data, experience with or general knowledge of the behaviour and properties of relevant materials, instruments, manufacturers' specifications, data provided in calibration and other certificates, and uncertainties assigned to reference data taken from handbooks.

3.24

wavelength deviation

$\Delta\lambda$

difference between the **centre wavelength** (3.4) measured by the test analyzer, λ_{OSA} , and the reference wavelength, λ_{ref} , in nm or μm

$$\Delta\lambda = \lambda_{\text{OSA}} - \lambda_{\text{ref}} \quad (7)$$

3.25

wavelength uncertainty

$\sigma_{\Delta\lambda}$

standard uncertainty (3.21) of the **wavelength deviation** (3.24), in nm or μm

4 Calibration test requirements

4.1 Preparation

The following recommendations apply.

Calibrations should be carried out in facilities that are separate from other functions of the organization. This separation should include laboratory accommodation and measurement equipment.

The calibration laboratory should operate a quality control system appropriate to the range of measurement it performs (for example, ISO 9000), when the calibration is performed in calibration laboratories. There should be independent scrutiny of the measurement results, intermediary calculations and preparation of calibration certificates.

The environmental conditions shall be commensurate with the degree of uncertainty that is required for calibration:

- a) the environment shall be clean;
- b) temperature monitoring and control is required;
- c) all laser sources shall be safely operated (see IEC 60825-1).

Perform all tests at an ambient room temperature of $23\text{ °C} \pm 3\text{ °C}$ with a relative humidity of $(50 \pm 20)\%$ unless otherwise specified. Give the test equipment a minimum of 2 h prior to testing to reach equilibrium with its environment. Allow the optical spectrum analyzer a warm-up period in accordance with the manufacturer's instructions.

4.2 Reference test conditions

The reference test conditions usually include the following parameters and, if necessary, their tolerance bands: date, temperature, relative humidity, displayed power level, wavelength, light source, fibre, connector-adapter combination, (spectral) bandwidth and resolution bandwidth (spectral resolution) set. Unless otherwise specified, use a single-mode optical fibre input pigtail as prescribed by IEC 60793-1, having a length of at least 2 m.

Operate the optical spectrum analyzer in accordance with the manufacturer's specifications and operating procedures. Where practical, select a range of test conditions and parameters which emulate the actual field operating conditions of the analyzer under test. Choose these parameters so as to optimize the accuracy of the analyzer and resolution capabilities, as specified by the manufacturer's operating procedures.

Document the conditions as specified in Clause 8.

NOTE 1 The calibration results only apply to the set of test conditions used in the calibration process.

NOTE 2 Because of the potential for hazardous radiation, be sure to establish and maintain conditions of laser safety. Refer to IEC 60825-1 and IEC 60825-2.

4.3 Traceability

Make sure that any test equipment which has a significant influence on the calibration results is calibrated in an unbroken chain to the appropriate national standard or natural physical constant. Upon request, specify this test equipment and its calibration chain(s). The re-calibration period(s) shall be defined and documented.

5 Resolution bandwidth (spectral resolution) test

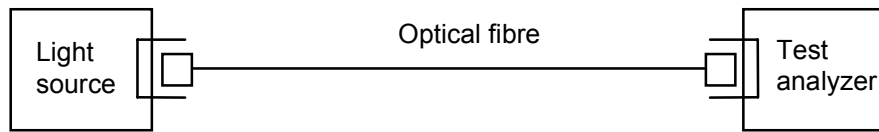
5.1 Overview

The resolution bandwidth (spectral resolution) of the test analyzer should be tested prior to displayed power level and wavelength calibration because the resolution bandwidth influences their calibration. This test is performed under reference calibration conditions. Wavelength is shown in a vacuum.

NOTE The result of the resolution bandwidth (spectral resolution) test described here should be employed as the optical bandwidth (in wavelength units) for the measurement of optical-amplifier noise-figure. The calibration of optical bandwidth is described in IEC 61290-3-1.

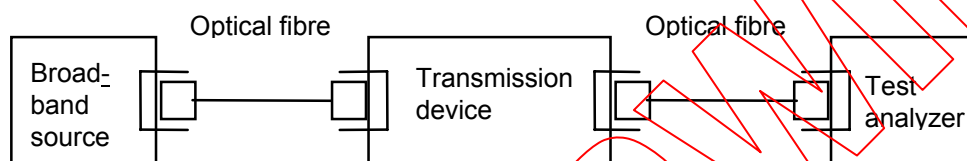
5.2 Resolution bandwidth (spectral resolution) test

Alternative set-ups for the resolution bandwidth are shown in Figures 1, 2, and 3. In the Figure 1 set-up, a gas laser whose wavelength is known is used as the light source. Figure 2 shows a set-up in which a broadband source is used in conjunction with a transmission device with known (traceable) wavelengths of peak (or null) transmission. Figure 3 shows a set-up in which a laser diode (LD) whose wavelength is unknown is used for the light source.



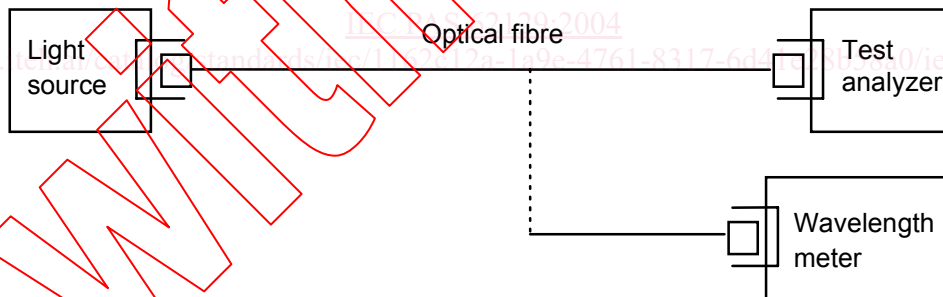
- a) for resolution bandwidth test,
- b) for wavelength calibration under reference conditions, and
- c) for determining the wavelength dependence of wavelength uncertainty.

Figure 1 – Set-up using a gas laser whose wavelength is known



- a) for resolution bandwidth test,
- b) for wavelength calibration under reference conditions, and
- c) for determining the wavelength dependence of wavelength uncertainty.

Figure 2 – Set-up using a broadband source with a transmission device



- a) for resolution bandwidth test,
- b) for wavelength calibration under reference conditions, and
- c) for determining the wavelength dependence of wavelength uncertainty.

Figure 3 – Set-up using an LD with an unknown wavelength

5.2.1 Equipment for resolution bandwidth (spectral resolution) test

- a) **Light source:** use the light source prescribed for calibrating the test analyzer; if a light source is not prescribed, use one with a spectral bandwidth and wavelength stability sufficient for the minimum resolution bandwidth prescribed for the test analyzer.

Recommended light sources are lasers such as those listed in Table 1, a laser diode (LD) or other laser (which may be tunable) having a spectral bandwidth much narrower than the resolution bandwidth of the test analyzer. Also, a broadband source may be used in conjunction with a transmission device with known (traceable) wavelengths of peak (or null)

transmission. The transmission device may be, for example, a series of fixed narrowband filters, absorption lines in gaseous media, or Fabry-Perot interferometers. Annex D tabulates many stable wavelength references. The reference used should have a wavelength stability, spectral bandwidth, and power stability sufficient for the resolution bandwidth test.

Table 1 – Recommended light sources

Light source	Wavelength (nm) [vac]
Ar laser	488,122
	514,673
He-Ne laser	632,991
	1152,590
	1523,488

- b) **Wavelength meter:** an instrument for measuring the wavelength of a light source. Its precision must be sufficiently better than the precision required in the wavelength test. This instrument is used when a laser diode (LD) with an unknown wavelength is used as the light source.
- c) **Optical fibre:** single-mode optical fibre as prescribed by IEC 60793-1.

5.2.2 Test procedure for resolution bandwidth (spectral resolution)

Using the test set-up shown in Figure 1, 2 or 3, set the wavelength measurement range of the test analyzer so that it includes the wavelength of the light source.

- a) Set the resolution bandwidth of the test analyzer to its specified value. Let the specified value be R_{set} .
- b) Measure the resolution of the displayed spectral bandwidth, that is, the wavelength interval 3 dB below the peak value, as R_{OSA_i} . Repeat this measurement at least ten times and calculate the average resolution.

$$R_{OSA} = \sum_{i=1}^m R_{OSA_i} / m \tag{8}$$

where m is the number of measurements.

- c) Calculate the difference ratio of the OSA value from the resolution bandwidth setting using equation (9).

$$\Delta r_{diff} = R_{OSA} / R_{set} - 1 \tag{9}$$

- d) If necessary, repeat this procedure with different resolution bandwidth settings.

NOTE 1 When the test analyzer has a wavelength span linearity error, it is necessary to tune the light source slightly around the wavelength of interest, while making multiple measurements of the displayed 3 dB bandwidth to obtain an accurate measurement of the true resolution bandwidth at a given wavelength. The required tuning range is of the order of ± 1 nm, so this measurement can be made with a temperature-tuned DFB laser, an external cavity laser or a tunable fibre laser. By averaging the resolution bandwidth readings, a more accurate measurement of the true resolution bandwidth can be obtained.

NOTE 2 If the resolution bandwidth should be corrected on the basis of the calibration results, this is typically implemented by making software corrections to the instrument, mathematical corrections to the results, or instrument hardware adjustments. Once the adjustments have been made, it is advisable to repeat the test to verify that the correction has operated correctly. See Annex C.